

ProSuite

The ultimate in application software



Automated Image Mapping

The Automated Image Mapping application enables users to automatically collect multiple images in a regular grid

Remote User Interface

Access the Phenom from a different location

ParticleMetric

Enables morphology and particle size data for submicron particle applications

3D Roughness Reconstruction

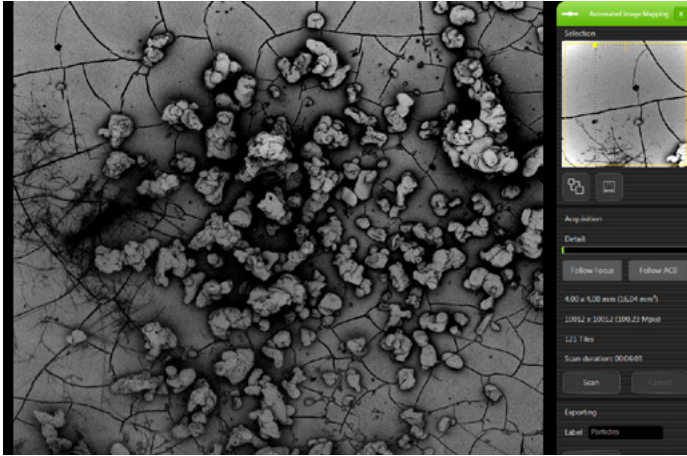
Generates three dimensional images and sub-micrometer roughness measurements

PoroMetric

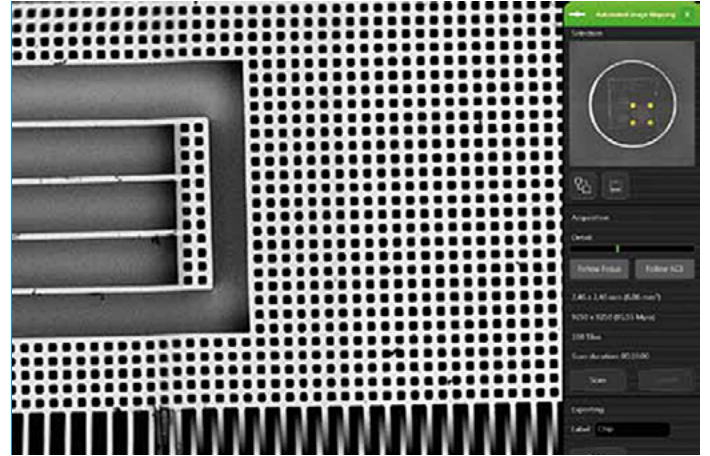
Enables automated visualization and analysis of pores

FiberMetric

Produces accurate size information from micro and nano fiber samples



The large overview (4 x 4 mm) shows all the particles on the sample



A close up of the image map revealing small details on the surface of the chip

The Phenom ProSuite was developed to extract information from images made with any Phenom desktop SEM desktop scanning electron microscope (SEM), and to automate complicated system control. This monitor mounted PC is the hardware platform for all ProSuite software, leaving the Phenom imaging unit in its original state and guaranteeing maximum system stability and up-time.

Standard applications

• Automated Image Mapping

The Automated Image Mapping application enables users to automatically collect multiple images in a regular grid.

• Remote User Interface

The Remote User Interface makes it possible to access the Phenom from a different location.

The ProSuite can be installed on any Phenom Pro, ProX and XL system. For the Phenom Pure system an additional completion package needs to be acquired. The ProSuite application platform can be connected directly to the Phenom or via a local network or the internet, enabling network storage and remote system control.

Applications

• 3D Roughness Reconstruction

With the 3D Roughness Reconstruction application, it is possible to generate three-dimensional images and sub-micrometer roughness measurements.

• FiberMetric

The FiberMetric application produces accurate size information from micro and nano fiber samples.

• PoroMetric

The PoroMetric application enables fully automated visualization and analysis of pores.

• ParticleMetric

The ParticleMetric application enables morphology and particle size data for submicron particle applications.

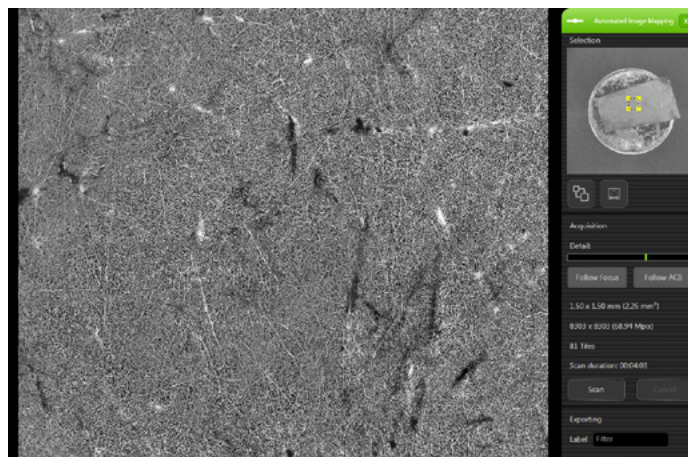
• Element Identification (EID)

The Element Identification software is a fully integrated software for X-ray analysis with precise spot mode function to identify hidden elements in any sample.

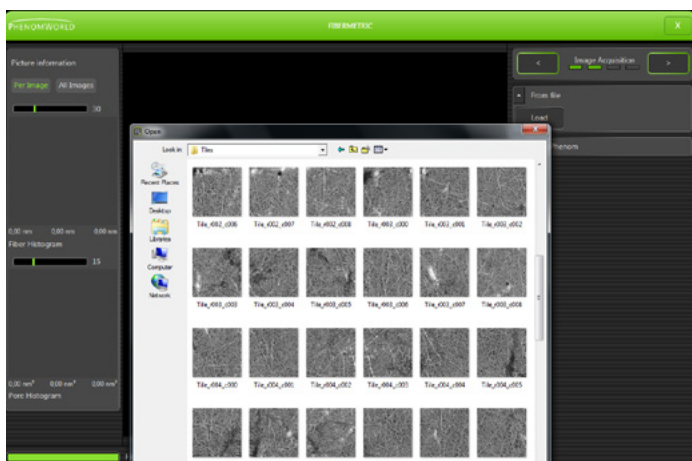
Automated Image Mapping



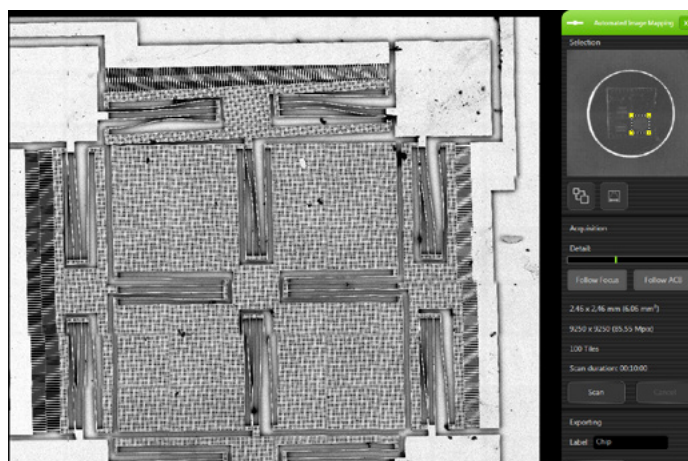
Example of large field of view automated image collection. The sample is a 3.15 x 4.15 mm ladybug that can be imaged completely at high resolution



Automated Image Mapping can be used to collect an array of images from a fiber sample. The application can take 100 images at 1024 x 1024 pixel within minutes



A batch of these images can be loaded into FiberMetric for fiber and pore size measurements



An overview of a 2.46 x 2.46 mm semiconductor scanned at high resolution, resulting in an 85 megapixel image

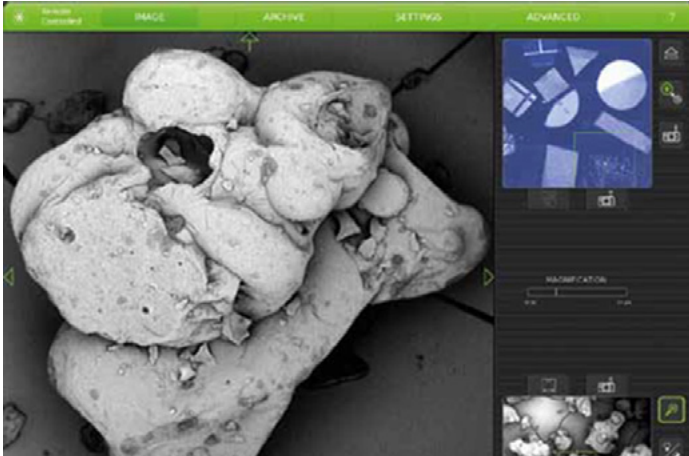
Automated Image Mapping

The Automated Image Mapping application enables user-defined collection of images with a large field of view on a high resolution image map. After an area has been defined in the overview, Automated Image Mapping scans the area at the desired resolution and number of images. The images are tiled to one large overview which can be stored and navigated for detailed observation. All images can be stored separately for image analysis or as a reference database.

Main benefits AIM

- Large field of view (FOV) images (min. magnification 31.8x, max. FOV 8.07 mm)
- Extremely high resolution complete sample image maps
- Automated procedure for collecting all sample image data
- Intuitive single page user interface
- Creation of low magnification overviews
- Automated acquisition for FiberMetric, PoroMetric and ParticleMetric

Remote User Interface



Remote controlled Phenom user interface



Phenom ProSuite

Remote User Interface

Remote User Interface makes it possible to access the Phenom desktop SEM from a different location. This application is ideal for customers needing support from Phenom-World service support to optimize the performance of their Phenom desktop SEM. The service support department can log on to the Phenom and help to adjust the necessary settings if access is granted from the customer's location.

The Phenom can be controlled using all the common features from the Phenom User Interface. It is also a perfect application for interacting with colleagues based at different locations. Samples can be imaged and data can be stored on a USB, a network location or local hard drive. This is the ideal solution for showing live results during a presentation or demonstration.

Main benefits Remote User Interface

- Real-time remote control
- Direct feedback from Phenom-World service support
- Interaction with colleagues at various locations

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